September 1999



ON Semiconductor®

FDS9431A

P-Channel 2.5V Specified MOSFET

General Description

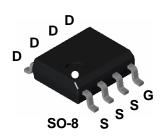
This P-Channel 2.5V specified MOSFET is produced using ON Semiconductor's proprietary, high cell density, DMOS technology. This very high density process has been especially tailored to minimize onstate resistance and yet maintain superior switching performance.

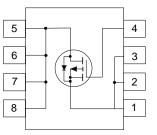
Applications

- DC/DC converter
- Power management
- · Load switch
- Battery protection

Features

- -3.5 A, -20 V. $R_{DS(ON)} = 0.130 \ \Omega \ @ V_{GS} = -4.5 \ V$ $R_{DS(ON)} = 0.180 \ \Omega \ @ V_{GS} = -2.5 \ V.$
- Fast switching speed.
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability.





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		±8	V
ID	Drain Current - Continuous	(Note 1a)	-3.5	A
	- Pulsed		-18	
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1.0	
T _J , T _{stg}	Operating and Storage Junction Temperat	ure Range	-55 to +150	°C

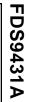
Thermal Characteristics

R _{θJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

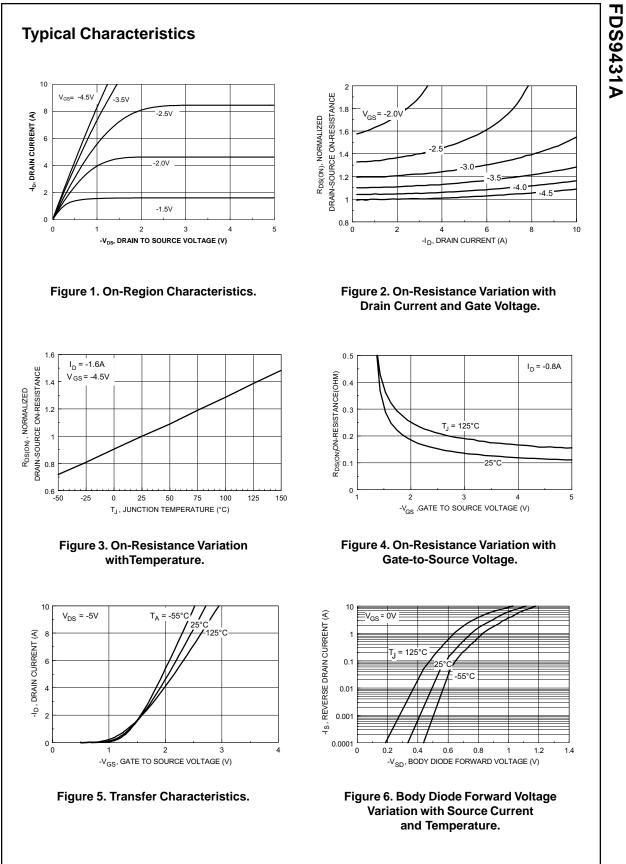
Package Marking and Ordering Information

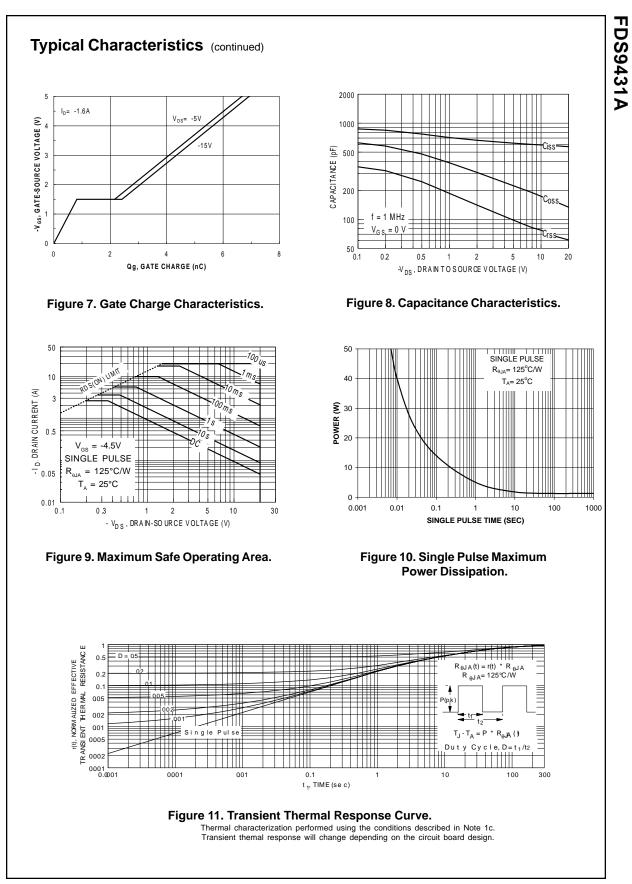
Device Marking	Device	Reel Size	Tape width	Quantity
FDS9431A	FDS9431A	13"	12mm	2500 units

eteristics rain-Source Breakdown Voltage reakdown Voltage Temperature oefficient ero Gate Voltage Drain Current ate-Body Leakage Current, orward ate-Body Leakage Current, everse	$\label{eq:VGS} \begin{array}{l} V_{GS} = 0 \ V, \ I_D = -250 \ \mu A \\ \\ I_D = -250 \ \mu A, Referenced \ to \ 25^\circ C \\ \\ V_{DS} = -16 \ \ V, \ V_{GS} = 0 \ V \\ \\ V_{GS} = 8 \ V, \ V_{DS} = 0 \ V \\ \\ \\ V_{GS} = -8 \ V, \ V_{DS} = 0 \ V \end{array}$	-20	-28	-1	V mV/°C
rain-Source Breakdown Voltage reakdown Voltage Temperature oefficient ero Gate Voltage Drain Current ate-Body Leakage Current, orward ate-Body Leakage Current, everse	$I_{D} = -250 \ \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$ $V_{DS} = -16 \ \text{V}, \ V_{GS} = 0 \ \text{V}$ $V_{GS} = 8 \ \text{V}, \ V_{DS} = 0 \ \text{V}$	-20	-28	-1	mV/°C
oefficient ero Gate Voltage Drain Current ate-Body Leakage Current, orward ate-Body Leakage Current, everse	$V_{DS} = -16$ V, $V_{GS} = 0$ V $V_{GS} = 8$ V, $V_{DS} = 0$ V		-28	-1	
ate-Body Leakage Current, orward ate-Body Leakage Current, everse	$V_{GS} = 8 V, V_{DS} = 0 V$			-1	^
orward ate-Body Leakage Current, everse					μA
everse	$V_{GS} = -8 V$, $V_{DS} = 0 V$			100	nA
toriction				-100	nA
teristics (Note 2)					
ate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250 \ \mu A$	-0.4	-0.6	-1	V
ate Threshold Voltage emperature Coefficient	I_D = -250 µA,Referenced to 25°C		2		mV/°C
tatic Drain-Source	$V_{GS} = -4.5 \text{ V}, I_D = -3.5 \text{ A}$		0.110	0.130	Ω
n-Resistance					Ω Ω
			0.100	0.220	52
n-State Drain Current	V _{GS} = -4.5 V, V _{DS} =-5 V	-10			A
orward Transconductance	$V_{DS} = -5 \text{ V}, \text{ I}_{D} = -3.5 \text{ A}$		6.5		S
haracteristics					
put Capacitance	$V_{DS} = -10 V, V_{GS} = 0 V,$		405		pF
output Capacitance	f = 1.0 MHz		170		pF
everse Transfer Capacitance	-		45		pF
Characteristics (Note 2)					
urn-On Delay Time	$V_{DD} = -5 V, I_D = -1 A,$		6.5	13	ns
urn-On Rise Time	V_{GS} = -4.5 V, R_{GEN} = 6 Ω		20	35	ns
urn-Off Delay Time	-		31	50	ns
urn-Off Fall Time	-		21	35	ns
otal Gate Charge	V _{DS} = -5 V, I _D = -3.5 A,		6	8.5	nC
	$V_{GS} = -4.5 V$				nC
ate-Source Charge	$V_{GS} = -4.5 V$		0.8		
ate-Source Charge	V _{GS} = -4.5 V		0.8 1.3		nC
ate-Drain Charge	-				
	and Maximum Ratings			-2.1	
	emperature Coefficient tatic Drain-Source n-Resistance n-State Drain Current orward Transconductance haracteristics put Capacitance everse Transfer Capacitance characteristics (Note 2) urn-On Delay Time urn-Off Delay Time urn-Off Fall Time	ate Threshold Voltage emperature Coefficient $I_D = -250 \ \mu\text{A}, \text{Referenced to } 25^\circ\text{C}$ ate Threshold Voltage emperature Coefficient $I_D = -250 \ \mu\text{A}, \text{Referenced to } 25^\circ\text{C}$ atic Drain-Source n-Resistance $V_{GS} = -4.5 \ V, \ I_D = -3.5 \ A \\ V_{GS} = -4.5 \ V, \ I_D = -3.5 \ A \\ T_J=125^\circ\text{C}$ n-State Drain Current $V_{GS} = -4.5 \ V, \ V_{DS} = -5 \ V$ porward Transconductance $V_{DS} = -5 \ V, \ I_D = -3.5 \ A \\ T_J=125^\circ\text{C}$ put Capacitance $V_{DS} = -5 \ V, \ I_D = -3.5 \ A \\ Put Capacitanceput CapacitanceV_{DS} = -10 \ V, \ V_{GS} = 0 \ V, \\ f = 1.0 \ MHzeverse Transfer CapacitanceV_{DD} = -5 \ V, \ I_D = -1 \ A, \\ V_{GS} = -4.5 \ V, \ R_{GEN} = 6 \ \Omega \\ Jrn-Off Delay Timeurn-Off Fall Timeurn-Off Fall Time$	ate Threshold Voltage emperature CoefficientID = -250 μ A, Referenced to 25°Catic Drain-Source n-ResistanceVGS = -4.5 V, ID = -3.5 A VGS = -2.5 V, ID = -3.0 A VGS = -4.5 V, ID = -3.5 A TJ=125°Cn-State Drain CurrentVGS = -4.5 V, VDS = -5 Vn-State Drain CurrentVGS = -4.5 V, VDS = -5 Vorward TransconductanceVDS = -5 V, ID = -3.5 Aharacteristics put CapacitanceVDS = -5 V, ID = -3.5 Aput CapacitanceVDS = -10 V, VGS = 0 V, f = 1.0 MHzcharacteristics urn-On Delay TimeVDD = -5 V, ID = -1 A, VGS = -4.5 V, RGEN = 6 Ω urn-Off Delay TimeVDD = -5 V, RGEN = 6 Ω urn-Off Fall TimeVDD = -4.5 V, RGEN = 6 Ω	ate Threshold Voltage emperature CoefficientID = -250 μ A,Referenced to 25°C2atic Drain-Source n-ResistanceVGS = -4.5 V, ID = -3.5 A VGS = -2.5 V, ID = -3.0 A VGS = -4.5 V, ID = -3.5 A T_J=125°C0.110 0.140 0.155n-State Drain CurrentVGS = -4.5 V, VDS = -5 V T_J=125°C-10n-State Drain CurrentVGS = -4.5 V, VDS = -5 V T_J=125°C-10n-State Drain CurrentVGS = -4.5 V, VDS = -5 V T_J=125°C-10n-State Drain CurrentVDS = -5 V, ID = -3.5 A6.5haracteristics put CapacitanceVDS = -10 V, VGS = 0 V, f = 1.0 MHz405uput CapacitanceVDS = -10 V, VGS = 0 V, f = 1.0 MHz45Characteristics urn-On Delay TimeVDD = -5 V, ID = -1 A, VGS = -4.5 V, RGEN = 6 \Omega20urn-Off Delay TimeVDD = -5 V, RGEN = 6 \Omega20urn-Off Fall Time21	ate Threshold Voltage emperature Coefficient $I_D = -250 \ \mu A, Referenced to 25^{\circ}C$ 2 atic Drain-Source n-Resistance $V_{GS} = -4.5 \ V, \ I_D = -3.5 \ A$ 0.110 0.130 n-Resistance $V_{GS} = -4.5 \ V, \ I_D = -3.5 \ A$ 0.140 0.140 n-Resistance $V_{GS} = -4.5 \ V, \ I_D = -3.5 \ A$ 0.110 0.130 n-Resistance $V_{GS} = -4.5 \ V, \ I_D = -3.5 \ A$ 0.140 0.180 n-State Drain Current $V_{GS} = -4.5 \ V, \ V_{DS} = -5 \ V$ -10 -10 prward Transconductance $V_{DS} = -5 \ V, \ I_D = -3.5 \ A$ 6.5 -10 put Capacitance $V_{DS} = -10 \ V, \ V_{GS} = 0 \ V, \ f = 1.0 \ MHz$ 170 -170 everse Transfer Capacitance $V_{DS} = -10 \ V, \ V_{GS} = 0 \ V, \ f = 1.0 \ MHz$ 405 -1170 urn-On Delay Time $V_{DD} = -5 \ V, \ I_D = -1 \ A, \ V_{GS} = -4.5 \ V, \ R_{GEN} = 6 \ \Omega$ 20 \ 35 31 \ 50 urn-Off Delay Time $V_{DS} = -4.5 \ V, \ R_{GEN} = 6 \ \Omega$ 21 \ 35 31 \ 50



2: Pulse Test: Pulse Width \leq 300 $\mu s,$ Duty Cycle \leq 2.0%





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